

## IC TEST HANDLER

## ABSTRACT OF THE DISCLOSURE

An IC test handler with a constant temperature chamber comprising six planet IC holders 71, a planet holder arranging mechanism 72, and an intermittent rotation driving mechanism for intermittently rotating the mechanism 72. Each planet IC holder has four surfaces S of rotation symmetric with respect to a shaft 71a for the planet, the four surfaces S functioning as IC holding parts. The planet IC holders are arranged in an annular array on the planet holder arranging mechanism 72 that can rotate around a shaft 72a for a sun. The six planet IC holders 71 can revolve around the shaft 72a for the sun while the mechanism 72 makes one rotation. The intermittent rotation driving mechanism intermittently rotates the planet holder arranging mechanism 72 an angle by an angle of  $60^\circ$  so that, when each planet IC holder 71 makes one revolution in the clockwise direction, it rotates by  $90^\circ$  on its own shaft. When a driving gear 73e and a solar gear 73b rotate, the six planet gears 73d slowly revolve around a shaft for the sun accompanied by the rotation of a rotating plate 73c while rotating in the clockwise direction on their own shafts. After 24 intermittent operations, the IC 4c attached to an IC holding part H is returned to its initial position. During this period, the temperature of the IC 4c on the IC holding part is sufficiently kept constant. Thereby, the number of preheated ICs in the IC constant temperature chamber can be increased, the tact period can be shortened, the staying time for the preheating can be elongated, and the space efficiency in the chamber can be improved.